An Introduction to Mixed-Signal IC Test and Measurement

Mark Burns
Texas Instruments, Incorporated

Gordon W. Roberts
McGill University

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Contents

Chapter 3: DC and Parametric Measurements

Chapter 4: Measurement Accuracy

Chapter 5: Tester Hardware

Chapter 6: Sampling Theory

Chapter 9: Sampled Channel Testing

Chapter 10: Focused Calibrations

Chapter 11: DAC Testing

Chapter 12: ADC Testing

Chapter 14: Design for Test (DfT)

Chapter 15: Data Analysis

Chapter 16: Test Economics